

Search Notes

Application/Control No.

09/771,464

Examiner

Hanh Nguyen

Applicant(s)/Patent und r
R examination

VANTTINEN ET AL.

Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
370	316	6/3/2006	HN
	312		
	332		
	352		
455	456.1		
	457		
	450		
	403		
	404.2		
	456.6		
	423		
	436		
	440		
	456.2		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	6/3/2006	HN